

NEW PRODUCT NEWS



BEAM CURRENT MONITOR

E. Fjeld Co., Inc. introduces a fast, effective method to monitor and maintain delivered beam current for specific scientific analysis. A self-contained, autoranging **Beam Current Monitor** allows the operator to monitor single-digit picoamps or hundreds of nanoamps. The easy-to-read LCD device installs quickly and consumes only 3 x 7 inches of operational space.

In addition, the Beam Current Monitor has been designed for ease of operation. Simply direct the electron beam into a Faraday Cup and power the Beam Current Monitor. The display will automatically illuminate the 3-digit LCD display. Autoranging begins immediately, precisely adjusting to the existing input current levels. The input range is 0 to -200 nA.

Ideal for EDS/WDS analysis or any operation requiring control and/or repetition of delivered beam current. Faraday attachments and elemental standards are available to complete the **Beam Current Monitor** package. PRICED @ \$985.00

E. Fjeld Co., Inc., 3 Executive Park Drive, N. Billerica, MA 01862
 (508)667-1416 - Fax: (508)667-9059
 Circle Reader Inquiry #40

DIAMOND KNIVES

EdgeCraft Corporation has announced the availability of Wet & Dry Cryo, Histo & Material Science Type 2 diamond knife versions for their EdgeCraft® Diamond Knife™ used for the preparation of sections for both electron & light microscopy. These products are in addition to their Standard Ultrathin EdgeCraft® Diamond Knife II™ introduced several months ago. In addition EdgeCraft has introduced a **NEW** World Wide Web site which can be accessed at <http://www.edgecraft.com>

EdgeCraft Corporation
 (800)343-3255 or (610)268-0500 - Fax: (610)268-3545
 eMail: info@edgecraft or diamondpa@aol.com
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Oxford Instruments Launches Link™ OPALMAP™

Link™ OpalMap™ drives the microscope electron beam over the sample to collect an electron backscattering pattern (EBSP) at each grid of points. Using advanced image processing techniques, the EBSP is solved to calculate the crystal orientation at each point. From this data, maps of the crystal orientation can be displayed and the microstructure of the sample regenerated. Capabilities of Link™ OpalMap™ go beyond an elementary combination of mapping and electron backscattered diffraction. Comprehensive software is supplied for grain boundary characterization and for studying the relationship between microtexture and grain orientations.

Oxford Instruments, Microanalysis Group: (508)369-9933, Fax: (508)369-8287
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